## Notice of References Cited Application/Control No. 10/034,352 Examiner Martin Lerner Applicant(s)/Patent Under Reexamination KAYAMA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0027369	02-2004	Kellock et al.	345/716
	В	US-2004/0133425	07-2004	Kawashima, Takahiro	704/258
	С	US-2003/0221542	12-2003	Kenmochi et al.	84/616
	D	US-2003/0009344	01-2003	Kayama et al.	704/500
	Е	US-2002/0184032	12-2002	Hisaminato et al.	704/268
	F	US-2002/0123990	09-2002	Abe et al.	707/3
	G	US-2002/0105359	08-2002	Shimizu et al.	327/1
	Н	US-			,
	1	US-			
	j	US-			
	К	US-		~	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

	· · · · · · · · · · · · · · · · · · ·						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р			<del>-</del> "			
	O			·			
	R	0					
	S						
	Т						

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.